

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Integrated circuits – Measurement of electromagnetic emissions –
Part 4: Measurement of conducted emissions – 1 Ω /150 Ω direct coupling
method**

**Circuits intégrés – Mesure des émissions électromagnétiques –
Partie 4: Mesure des émissions conduites – Méthode par couplage direct
1 Ω /150 Ω**



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IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
info@iec.ch
www.iec.ch

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**INTEGRATED CIRCUITS –
MEASUREMENT OF ELECTROMAGNETIC EMISSIONS –****Part 4: Measurement of conducted emissions –
1 Ω /150 Ω direct coupling method**

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This second edition cancels and replaces the first edition published in 2002 and Amendment 1:2006. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) frequency range of 150 kHz to 1 GHz has been deleted from the title;
- b) recommended frequency range for 1 Ω method has been reduced to 30 MHz;
- c) Annex G with recommendations and guidelines for frequency range extension beyond 1 GHz has been added.

The text of this International Standard is based on the following documents:

Draft	Report on voting
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Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/standardsdev/publications.

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